EM injection Clamps for IEC 61000-4-6

Fischer Custom Communications, Inc. offers two EM injection Clamps, model F-2031-23mm and F-2031-32mm. FCC EM Injection Clamps offer unique benefits.



- High efficiency coupling factor, <3 dB from 150 kHz 500 MHz
- F-2031-32mm is ideal for testing multi-conductor cables
- FCC offers all of the test accesories required for testing with the EM Injection Clamps including clamp-on current monitor probes, calibration fixtures and ferrite tube decoupling networks with 23 mm and 32 mm apertures.

Test Setup Using the EM Clamp and a Ferrite Tube Decoupling Network

The electromagnetic (EM) clamp is a high efficiency broadband clamp-on injection device developed to test the immunity of electronic equipment when the standard IEC 1000-4-6 CDN using the direct capacitive coupling technique is not possible nor appropriate. The EM Clamp is often used to test unshielded multiple conductor cables. The figure below shows a typical test setup using the EM Clamp and a ferrite tube decoupling network.



Fig. 1: Test Setup/EM Clamp & Ferrite Tube Decoupling Network

Specifications for Models: F-2031-23mm & F-2031-32mm

Specification	F-2031-23mm	F-2031-32mm
Input Power Rating - 10KHz to 100 MHz: - 100 MHz to 230 MHz: - 230 MHZ to 1GHz:	100 watts CW for 15 minutes 100 watts CW for 10 minutes 50 watts CW for 10 minutes	125 watts CW for 30 minutes 100 watts CW for 30 minutes 100 watts for 15 minutes
Pulse Mode:	Transients of 3 nanosecond rise nanoseconds can be coupled interesting the coupled interesting of the second secon	times and pulse widths of 100 o cables up to 5 KV
Directivity:	>10dB above 20 MHz	>10 dB above 20 MHz
Coupling Aperture: - Length - Width - Height including handle - RF connector	23 mm 610 mm 75 mm 135 mm N	32 mm 610 mm 105 mm 190 mm N
-8 -8 -10 -10 -12 -14 -14 -14 -14 -10	1 10 Frequency (MH;	z) 100 1000
K Factor (dB)		

Figure 2: Typical Insertion Loss and K Factor for the F-2031-23mm

1

0.1

10 Frequency (MHz)

100

1000

RF electromagnetic fields frequently degrade electronic equipment by generating common mode currents on cables. The effect of these E and H fields on the equipment

can be simulated by injecting common mode currents into the cables of the equipment being tested for RF immunity. IEC 1000-4-6 defines the methods for testing the immunity of electronic equipment to conducted mode currents between 150 kHz and 230 MHz.

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For conducted immunity testing from 150 kHz to 230 MHz the increased efficiency can save the user as much as 100% on required CW amplifier power. The F-203I family requires less than 10 watts to develop the 10 volt open circuit level in accord with the IEC 1000-4-6. When an additional ferrite decoupling or ferrite tube is used in the test the F-203I family requires less than 36 watts to develop the 10 volt open circuit level.